FMI Commercial "New" Space Products

Crystals & Oscillators for SmallSat & CubeSat Applications

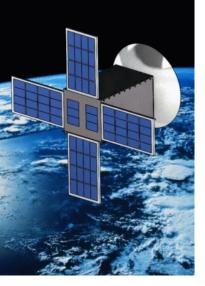


Performance Excellence | Smallest & Lightest Product Offerings | Hi-Rel & Low Cost

Compelling Frequency & Timing Solutions for Mission Success **F**MI

www.FrequencyManagement.com





Mission Success Optimized Cost

Frequency Control Solutions for Commercial Space Missions

SmallSat CubeSat Nanosat

FMI has been at the forefront of providing the most reliable timing devices and clock solutions to the ever-expanding market for space missions utilizing miniature scale electronics, often referred to as CubeSat, SmallSat and Nanosat, etc. Our customers have been selecting from our standard product offering for miniaturized commercial space (C-Series) which benefits from years of FMI's extensive development in miniature scale, highly reliable and cost-efficient solutions used in commercial high reliability applications. We are uniquely blending the best attributes of cost effective assemblies used in industrial/telecomm applications with the benefits for a wide variety of space applications.

The FMI C-Series product offering is a direct response to the need for satellite miniaturization that often correlates with diverse mission life objectives. The C-Series offers optimum solutions for the ever-expanding scope of CubeSat and SmallSat missions as well as constellations of small spacecraft.

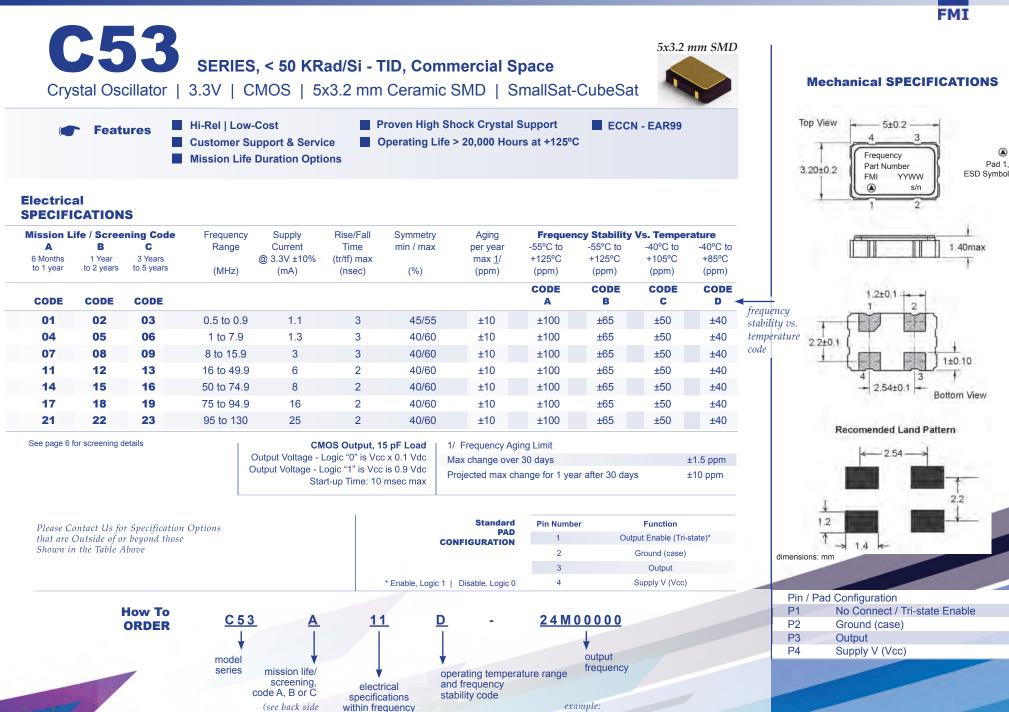
In pioneering the efficient and miniaturized commercial space grade clock solutions, FMI takes a strong position to encourage the industry to contribute and reduce any potential space debris regardless of the applications mentioned above which may include IoT and M2M small satellite networks or the satellites that may be utilized for remote sensing.

FMI is uniquely prepared to efficiently respond to the timing and frequency control requirements of miniaturized satellite designers and manufacturers.



FMI Model





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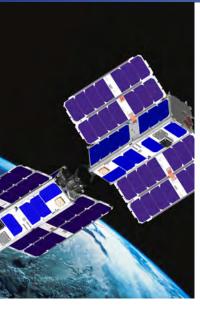
C53A11D-24M00000

of data sheet)

range / tri-state

option code

FMI Model



Customer Selected Mission Life



C73 SERIES, including package variations C88, C83 & C78 < 50 KRad/Si - TID, Commercial Space
Crystal Oscillator 3.3V CMOS 5x7mm Ceramic SMD and Leaded Versions SmallSat-CubeSat

Features Hi-Rel | Low-Cost Customer Support & Services Mission Life Duration Options

- Proven High Shock Crystal Support
 Operating Life > 20,000 Hours at +125°C
- ECCN EAR99

(

Electrical

SPECIFICATIONS

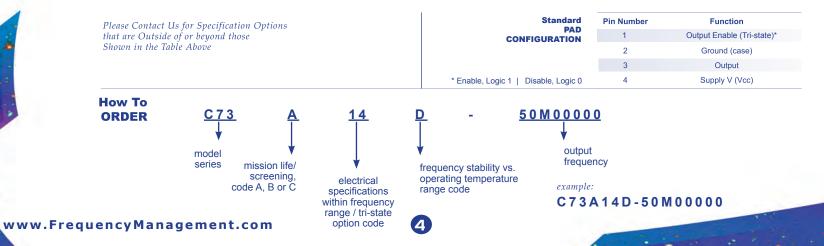
See page 6 for screening details

Mission L	.ife / Scree	ning Code	Frequency	Supply	Rise/Fall	Symmetry	Aging	Freque	ncy Stability	Vs. Tempe	rature	
A 6 Months to 1 year	B 1 Year to 2 years	C 3 Years to 5 years	Range (MHz)	Current @ 3.3V ±10% (mA)	Time (tr/tf) max (nsec)	min / max (%)	per year max <u>1</u> / (ppm)	-55°C to +125°C (ppm)	-55°C to +125°C (ppm)	-40°C to +105°C (ppm)	-40°C to +85°C (ppm)	
CODE	CODE	CODE						CODE A	CODE B	CODE C	CODE D	
01	02	03	0.5 to 0.9	1	3	48/52	±10	±100	±60	±50	±40	frequenc stability
04	05	06	1 to 7.9	1.2	3	48/52	±10	±100	±60	±50	±40	temperat
07	08	09	8 to 15.9	3	3	45/55	±10	±100	±60	±50	±40	code
11	12	13	16 to 49.9	6	3	45/55	±10	±100	±60	±50	±40	
14	15	16	50 to 79.9	8	2	40/60	±10	±100	±60	±50	±40	
17	18	19	80 to 94.9	10	2	40/60	±10	±100	±60	±50	±40	
21	22	23	95 to 130	25	2	40/60	±10	±100	±60	±50	±40	

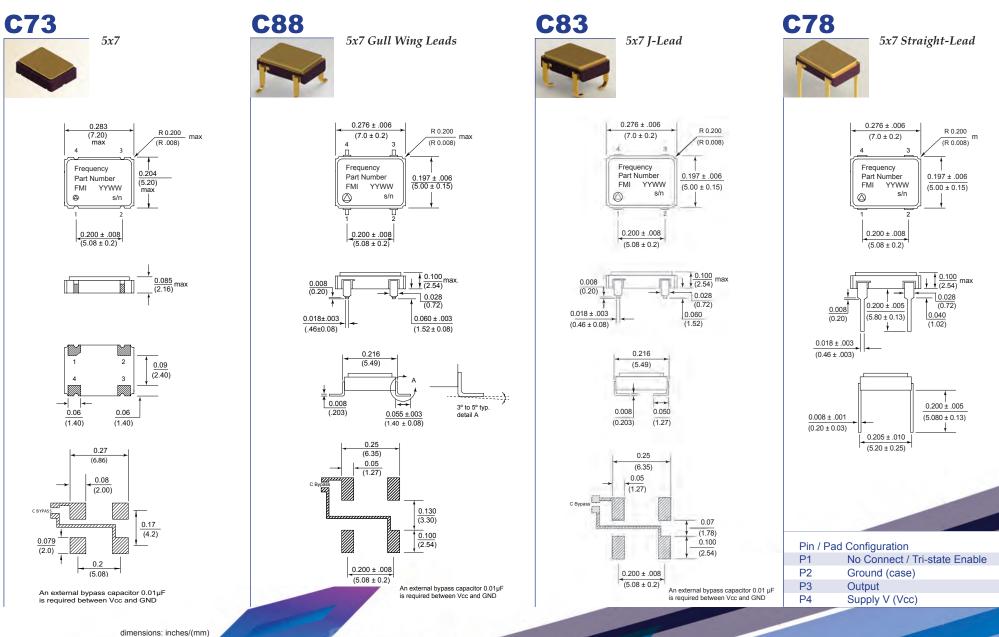
CMOS Output, 15 pF Load	1/
Output Voltage - Logic "0" is Vcc x 0.1 Vdc	Ma
Output Voltage - Logic "1" is Vcc is 0.9 Vdc Start-up Time: 10 msec max	

/ Frequency Aging Limit Nax change over 30 days

ax change over 30 days±1.5 ppmrojected max change for 1 year after 30 days±10 ppm







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dimensions. inches/(inin)

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Solutions for High-Performance Low-Cost Missions





3.2 x 2.5 mm Ceramic SMD Smallest Package Footprint Available Please Contact Us For Details Product Highlight

Mission Life Screening- A, B & C OPTIONS						
Screening	Method Options:	Α	В	C		
Non-Destruct Bond Pull	MIL-STD-883, Method 2023	•	•	•		
Internal Visual	MIL-STD-883, Method 2017	•	•	•		
Stabilization (Vacuum) Bake	MIL-STD-883, Method 1008, Condition C, 150°C, 24 hours min	•	•	•		
Temperature Cycling	MIL-STD-883, Method 1010, Condition B, 10 Cycles	•	•	•		
Constant Acceleration	MIL-STD-883, Method 2001, Condition A (Y1 only, 5000 g's)		•	•		
PIND Test	MIL-STD-883, Method 2020, Condition B, 5 passes max			•		
Seal: Fine Leak	MIL-STD-883, Method 1014, Condition A1			•		
	MIL-STD-202, Method 112, Condition C, 111A		•			
Seal: Gross Leak	MIL-STD-202, Method 112, Condition D	•	•	•		
Electrical Test	Functional Test Only at +23°C	•	•	•		
Marking & Serialization	MIL-STD-1285	•	•	•		
Electrical Test	Nominal Vcc & Extremes and Nominal Temp and Extremes		•	•		
Burn-in (load)	+125°C, Nominal Supply Voltage and Burn-in load, 160 hours min		•	•		
Burn-in (no-load)	+125°C, Nominal Supply Voltage and Burn-in load, 48 hours min	•				
Interim Electrical	Functional Test Only			•		
Burn-in (load)	+125°C, Nominal Supply Voltage and Burn-in load, 160 hours min			•		
		•	•	•		
Radiography	MIL-STD-883, Method 2012			•		
Frequency Aging	MIL-PRF-55310, +70°C Condition			•		
Frequency/Temperature Stability	MIL-PRF-55310, Over temperature extremes, 20 points equally spaced			•		
External Visual & Mechanical	MIL-STD-883, Method 2009	•	•	•		

note: other options, screening levels and custom test plans available.

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Eliminating the Need for System Component Redundancy

Environmental COMPLIANCE						
Environmental	Specification	Method	Condition			
Vibration – Sine	MIL-STD-202	Method 204	Condition D 20g, 10 to 2 KH	lz		
Vibration – Random	MIL-STD-202	Method 214	Condition 1 30g rms, 10 to 2	KHz Random		
Shock	MIL-STD-202	Method 213	Condition I 100g, 6 ms, F:1	500, 0.5 ms		
Seal Test	MIL-STD-883	Method 1014	Condition A1 Fir	ie Leak		
Seal Test	MIL-STD-883	Method 1014	Condition C1 Gr	oss Leak		
Temperature Cycling	MIL-STD-883	Method 1010	Condition B 10 Cycles Minir	num		
Constant Acceleration	MIL-STD-883	Method 2001	Condition A 5000g, Y1 Axis			
Thermal Shock	MIL-STD-202	Method 107	Condition B			
Ambient Pressure	MIL-STD-202	Method 105	Condition C			
Resistance to Soldering Heat	MIL-STD-202	Method 210	Condition C			
Moisture Resistance	MIL-STD-202	Method 106	with 7B Sub-cycle			
Salt Atmosphere (corrosion)	MIL-STD-883	Method 1009	Condition A (24 hrs)			
Terminal Strength	MIL-STD-202	Method 211	Test Condition D			
Solderability	MIL-STD-883	Method 2003				
Resistance to Solvents	MIL-STD-202	Method 215				

Packaged Crystals for Space Applications

8 MHz to 150 MHz Crystals in ruggedized 5x7 mm smd packages. These crystals are also available in a variety of both thru-hole and smd packages. Please inquire.



Contact Us

Frequency Management International 15302 Bolsa Chica Street Huntington Beach, CA 92649

tel: 714 373 8100 fax: 714 373 8700 toll free (USA): 800 800 9825

Sales@FrequencyManagement.com

Qualification & Specification References

MIL-STD-202

MIL-STD-883

MIL-STD-790 Certified FMI is QPL per MIL-PRF-55310 ISO 9001:2015 Pb-free RoHS Certified

Military Reference Specifications

MIL-PRF-55310 Oscillators, Crystal Controlled, General Specification For MIL-PRF-38534 Hybrid Microcircuits, General Specification For Test Method Standard, Electronic and Electrical Components Test Methods and Procedures for Microelectronics MIL-STD-1686 Electrostatic Discharge Control Program for Protection of Electrical and Electronic Parts, Assemblies and Equipment

Materials

1. Package Materials: Ceramic, Alumina 90% min

2. External Lead Plating Material: Gold plated Kovar, 0.15 µm (60 µ inch) min, over 2.0 µm (80 µ inch) min Nickel

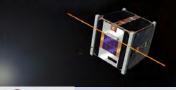
Products for Space Applications

Contact us for assistance with your specification. We will provide you with the technical support and the required documentation.

FREQUENCY MANAGEMENT | International 15302 Bolsa Chica Street Huntington Beach, CA 92649

> Sales@FrequencyManagement.com Tel. 714 373 8100 Fax. 714 373 8700 **800 800 9825 (USA Only)**

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Designed Specifically for Lower-Cost Space Missions

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